

Appl	licati	on/	Con	trol	No
10/8	13,6	374			

Examiner shih-wen hsieh

Applicant(s)/Patent under Reexamination CHIUN, KUAN TA

Art Unit 2861

				ISSUE	CL	.AS	SIF	ICAT	ION			
	INTERNATIONAL CLASSIFICATION											
(LASS CLAIMED						NON-CLAIMED					
347 22			?	В	4	1	J	2/165			1	
	CRO	SS REFEREI	NCES						,			
CLASS	R BLOCK)											
347	23	29	30	33					1			1 .
									<i>1</i>			1
												1
									1			1
									1			1 .
Mus Well Striff (Primary					-WEI RY E	NAX MAX	EH INEP	P-07		ed: 14		
					(Primary Exampler) (Date)					O.G. Print Claim(s)		
(Legal/Instruments Examiner) (Date)										3A&3		

	laims	ns renumbered in the same order as presented by applicant								□СРА			☐ T.D.			☐ R.1.47			
Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original
1	1			31			61	1		91			121			151			181
	2	1		32			62	1		92			122			152		,	182
2	3			33			63			93	,		123			153			183
3	4			34			64			94			124		Δ	154.			184
4	5			35			65	1		95			125			155	•		185
5	6			36			66			96			126			156			186
6	7			37			67	-11		97			127			157			187
7	8			38			68			98			128			158			188
8	9			39			69			99			129			159			189
9	10		777	40			70			100			130			160			190
	11			41			71			101			131			161			191
10	12	1		42			72			102			132			162			192
11	13	1 1		43	,		73	1		103			133			163			193
12	14	1		44			74			104			134			164			194
13	15	1		45			75	1		105			135			165			195
14	16			46			76	1		106			136			166			196
	17	1		47			77	1		107			137			167			197
	18	1		48			78	1		108			138			168			198
	19	1		49			79	1		109			139			169			199
	20	1		50			80	1		110			140			170			200
	21	1		51			81	1		111			141			171			201
	22	1		52			82	1		112			142			172			202
	23	1		53			83] .		113			143			173			203
	24	1		54			84	1		114			144			174			204
	25	1		55			85	1		115			145			175			205
	26	1		56			86	1		116			146			176			206
	27	1		57			87			117			147			177			207
	28	1		58			88	1		118			148			178			208
	29	1		59			89]		119			149			179			209
	30	1		60	1		90			120			150			180			210